Full Automatic ESD Tester

HED-G5000 series

- Ultra low parasitic high-pin count ESD Tester
- Perfectly possible to pin combination testing
- Conforms to JEDEC, ESDA, AEC and JEITA standards

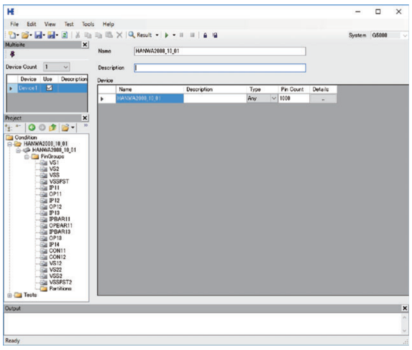
HANWA Hanwa Electronic Ind. Co., Ltd.

Specification

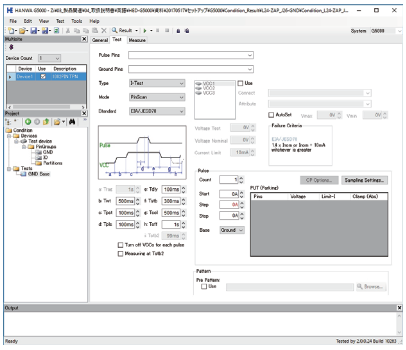
Adaptable to the following international standard waveform;
ESDA_JEDEC JS-001(AEC), JEITA
This system’ s uniquely short discharge circuit is made possible by its original mechanical design. The short circuit minimizes the influence of inductance and capacitance on the data. Further, the use of a single circuit ensures data stability for each device pin tested.

Design Base	Mechanical
Matrix	No relay system
Test Model	HBM, MM, & Latch Up Customize Available
Test Level	HBM:10V to 8kV step 5V
	MM:10V to 4kV step 5V
	Latch Up:100V/1A, 35V/1A
Latch Up	JESD78 with Vector Option
Vector	10MHz max, 0.5-5V, 256k depth,
Pin count	Max 2048 Customize Available
DUT V/I Supplies	Max 8:100V/1A, 35V/1A, 1A/100V
Dimensions	200cm(W)×105cm(D)×150cm(H) Depend on System
Weight	500kg
Operation System	Windows
AC Voltage	100 -240V/20A

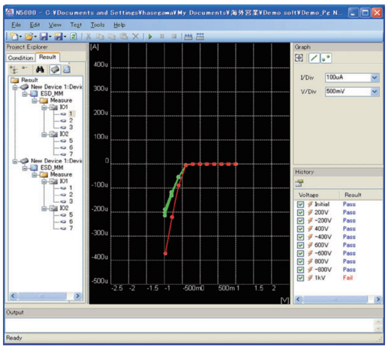
Application view



Condition



Measurement



Graph mode

Features

Single discharging circuit

New, specialized mechanical GND setting
Low parasitic capacitance

Max 2048 pins

Can be used with various standard waveforms

This high-quality system conforms to a number of international standards, including ESDA_JEDEC JS-001(AEC), JEITA.

Can be used with latch-up testing

Easy and reliable operation

Much shorter testing procedure

This device uses mercury relays.
If you have any questions, please contact us.

HANWA

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■ Agency

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